

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

SHEET 2 of 2

Complete if Known

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| Application Number | 10/565,030 |
| Filing Date | January 22, 2007 |
| First Named Inventor | Daniel Mansfield |
| Art Unit | 2877 |
| Examiner Name | Not Yet Known |
| Attorney Docket No. | AMTH-104US |

NON-PATENT LITERATURE DOCUMENTS

| Examiner Initials* | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published | T ² |
|--------------------|-----------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------------------|
| | | International Search Report for PCT/GB2004/003066; Completed November 23, 2004. | <input type="checkbox"/> |
| | | UK Search Report Under Section 17 for PCT/GB 0316916.6; Completed January 7, 2004. | <input type="checkbox"/> |
| | | <i>Testing Aspheric Surfaces Using Multiple Annular Interferograms</i> ; MAURO MELOZZI, LUCA PEZZATI, ALESSANDRO MAZZONI Optical Engineering, May 1993, Vol 32 No. PP. 1073-1079. | <input type="checkbox"/> |
| | | <i>Optical Shop Testing</i> ; Chapter 1, Edited by DANIEL MALACARA, Second Edition, Published 1992. | <input type="checkbox"/> |
| | | <i>PROFILMETRY WITH A COHERENCE SCANNING MICROSCOPE</i> ; BRYAN S. LEE ET AL.; Applied Optics, Vol. 29, No. 26, September 10, 1990, PP. 3784-3788. | <input type="checkbox"/> |
| | | <i>Three-Dimensional Imaging by sub-Nyquist Sampling of White-Light Interferograms</i> ; PETER DE GROOT AND LESLIE DECK; Optics Letters, September 1, 1993; Vol. 18, No. 17. | <input type="checkbox"/> |
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| Examiner Signature | | Date Considered | |
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

¹Applicant's unique citation designation number (optional).

²Applicant is to place a check mark here if English language translation is attached.

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